



Side-Channel Analysis of the TERO PUF

Lars Tebelmann¹ Michael Pehl¹ Vincent Immler²

¹Technical University of Munich, München, Germany

²Fraunhofer AISEC, Garching bei München, Germany

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Agenda

Introduction PUFs and Attacks On PUF Primitives The Transient Effect Ring Oscillator (TERO) The TERO PUF Architecture

Our Approach Experimental Setup Attack Sketch Preliminary Experiments Short Time Fourier Transform (STFT) Approach

Exploitation of the TERO Side-Channel Proof of Concept: Single Cells Scenario 1: Simultaneous Cells Scenario 2: Multi-bit Responses

Summary and Future Work





Physical Unclonable Functions (PUFs)

- Randomness from manufacturing variations
 - Hardware-intrinsic features
 - "Fingerprint" of a device
- Alternative for secure low-cost key storage
 - Key generation during run time
 - No key material on device after power-off



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Side-Channel Analysis of PUF Primitives

- SRAM: semi-invasive, photon emission
 - ► Helfmeier et al.: Cloning Physically Unclonable Functions. HOST 2013
- Arbiter PUF: semi-invasive, photon emission
 - ► Tajik et al.: Physical Characterization of Arbiter PUFs. CHES 2014
- RO PUF: semi-invasive, Laser Voltage Probing
 - ► Lohrke et al.: No Place to Hide: Contactless Probing of Secret Data on FPGAs. CHES 2016
- RO PUF: semi-invasive, localized EM
 - Merli et al.: Semi-invasive EM Attack on FPGA RO PUFs and Countermeasures. WESS 2011
 - ► Merli et al.: Electromagnetic Analysis of RO PUFs. HOST 2013

In this talk: non-invasive attacks on TERO PUF based on EM



The Transient Effect Ring Oscillator (TERO)¹



- Metastable oscillations
 - Two propagating events upon enable
 - Ideal: Oscillation until reset
 - Real: Oscillation stops after Tosc

- Applications
 - ► TRNGs¹
 - Primitive for PUFs

¹Varchola/Drutarovsky: *New High Entropy Element for FPGA Based True Random Number Generators*. Cryptographic Hardware and Embedded Systems (CHES), 2010 Tebelmann et al. | Side-Channel Analysis of the TERO PUF 5 / 19





The TERO PUF Architecture¹

- Select one cell per block (Challenge)
- Enable cells for $T_{acq} = 600 \text{ ns}$
- Response: stable subtractor bits
 - Single-bit: MSB only
 - Multi-bit: further LSBs
- Claimed advantage¹ over RO: no side-channel weakness



¹Marchand et al.: *Design and Characterization of the TERO-PUF on SRAM FPGAs.* IEEE Computer Society Annual Symposium on VLSI (ISVLSI), 2016 Tebelmann et al. | Side-Channel Analysis of the TERO PUF 6 / 19



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Experimental Setup



Measurement setup

- Xilinx Spartan-6 LX16
- Near-field probe
- Sampling oscilloscope (20 GS/s)



Target floorplan

- TERO PUF: 2 \times 96 cells
- Adjacent counters



Attack Sketch

Strategy:

- 1. Measure TERO oscillation with EM probe and oscilloscope
- 2. Observe oscillation duration in time-frequency domain
- 3. Derive counter values from oscillation duration
- 4. Reveal secret

Requirements:

- 1. TEROs oscillate with approx. same frequency
- 2. Oscillations are observable
- 3. Strategy to derive oscillation duration

Discovering TERO Oscillations: Do TEROs oscillate with the same frequency?

- Run TEROs for different T_{acq}
- Read out counter values Nosc
- Slope: Constant oscillation frequency

$$f_{TERO} = rac{\Delta N_{osc}}{\Delta T_{acq}} pprox 187.5\,\mathrm{MHz}$$

 \Rightarrow Estimate N_{est} of counter value by oscillation time T_{osc}

$$N_{est} = f_{TERO} \cdot T_{osc} \approx N_{osc}$$









Preliminary Experiments

EM Cartography: Are TERO oscillations observable?





Preliminary Experiments

EM Cartography: Are TERO oscillations observable?





Short Time Fourier Transform (STFT) Approach

Strategy to derive oscillation duration

- STFT spectrogram from time domain signals
 - Alternative: spectrum analyzer
- Estimate: $N_{est} \approx f_{TERO} \cdot T_{osc}$







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Proof of Concept: Single Cells

Spectral Analysis



Accurate estimate for short and long oscillations





Proof of Concept: Single Cells

Estimated vs. Real Counter Values

- Automatic detection of counter values by SNR threshold
- Estimate and actual counter value match
- Realistic values: 10 ≤ N_{est} ≤ f_{TERO} · T_{acq} ≈ 112
- TERO oscillations approximated by STFT method







Scenario 1: Simultaneous Cells



- Realistic scenario¹: activate cell from each block simultaneosly
- Challenge selects cells for activation
- Overlapping comparison of cells results in up to

 $M \cdot M = 96 \cdot 96 = 9216$ PUF bits

¹Marchand et al.: *Design and Characterization of the TERO-PUF on SRAM FPGAs.* IEEE Computer Society Annual Symposium on VLSI (ISVLSI), 2016 Tebelmann et al. | Side-Channel Analysis of the TERO PUF 14 / 19





Scenario 1: Simultaneous Cells

Estimated vs. Real Counter Values

Attack Strategy:

- Average over all SNRs for a cell
- · SNR from other cells cancel out
- ⇒ Results similar to Proof of Concept
 - Manual inspection of SNR can reveal unreliable estimates







Scenario 1: Simultaneous Cells

Reducing the Entropy of the TERO PUF

- Predict PUF bits from comparison of different N_{est}
- Difference of counter estimates $\Delta_{est} = N_{est,0}^i N_{est,1}^j$ indicates reliability of PUF bit estimate
 - Smart guessing: sorting by Δ_{est}
- Overall error of 17%
 - manually improved to 14.7%
- Design under attack with overlapping comparison broken considering PUF error correction.







Scenario 2: Multi-bit Responses



- Countermeasure: only pairwise comparison
 - (+) One measurement per cell: No averaging possible
 - (+) Sign bit cannot be attacked
 - (-) Less PUF bits
- Extension¹: Derivation of multiple bits, i.e., difference of counters
 (+) More PUF bits per comparison

New attack: retrieve difference

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- Attack succeeds in many cases
 - Two oscillation durations can be observed
 - Resolution accurate enough to distinguish differences
- Deviating SNR behaviour can be modelled (c.f. paper)
- Entropy reduced to sign bit





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Summary and Future Work





Summary and Future Work

- TERO PUF prone to side-channel analysis
- PoC: Oscillations of TEROs approximated by STFT methods
- Scenario 1: TERO PUF with overlapping comparisons broken
 - Overall error in the range of error correction for PUFs
 - ► Confidence of PUF bits based on estimate differences: smart guessing
- Scenario 2: Multi-bit responses reduced to sign bit
 - Only pairwise comparison impedes attack, but reduces PUF bits
 - Derivation of multiple bits prone to side-channel attack
- Future work
 - Further attack potential: spectrum analyzer, advanced evaluation method, semi-invasive attack, ...
 - Possible counter measures





Thank You!

Lars Tebelmann

lars.tebelmann@tum.de
https://www.sec.ei.tum.de/